

Notice of References Cited	Application/Control No. 10/554,630		Applicant(s)/Patent Under Reexamination AIZAWA ET AL.	
	Examiner ARCHENE TURNER		Art Unit 1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,221,493 B1	04-2001	Reineck et al.	428/469
*	B	US-6,214,247 B1	04-2001	Leverenz et al.	216/56
*	C	US-6,110,240 A	08-2000	Saguchi et al.	51/307
*	D	US-5,985,427 A	11-1999	Ueda et al.	428/698
*	E	US-5,915,162 A	06-1999	Uchino et al.	428/699
*	F	US-5,912,162 A	06-1999	Liu et al.	435/252.5
*	G	US-5,038,645	08-1991	Walter et al.	407/119
*	H	US-4,169,913	10-1979	Kobayashi et al.	428/698
*	I	US-4,105,443	08-1978	Dearnaley et al.	75/238
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2001341008	11-2001	JP	Hitachi Tool	---
	O	11302830	11-1999	JP	Tokyo	---
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.